

Image

2881  
PATENT

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re application of: Shing M. Lee

Attorney Docket No.: KLA1P012/P647US

Application No.: 09/695,726

Examiner: Fernandez, K.

Filed: October 23, 2000

Group: 2881

Title: FILM THICKNESS MEASUREMENT  
USING ELECTRON-BEAM INDUCED  
X-RAY MICROANALYSIS

CERTIFICATE OF MAILING

I hereby certify that this correspondence is being deposited with the United States Postal Service as First-Class Mail to: Commissioner for Patents, P.O. Box 1450, Alexandria, VA 22313-1450, on February 3, 2004.

Printed Name: Leslie Russell

Signed: 

TRANSMITTAL

Commissioner for Patents  
P.O. Box 1450  
Alexandria, VA 22313-1450

Sir:

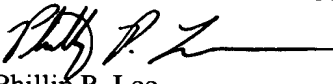
Transmitted herewith is a Statement of the Substance of the Interview in the above-identified application.

The fee has been calculated as shown below.

	Claims After Amendment		Highest Previously Paid For	Present Extra	Small Entity Rate Fee	Large Entity Rate Fee
Total Claims	28	MINUS	30	00	x 9 =	x 18 = 0.00
Independent Claims	03	MINUS	06	00	x 42 =	x 84 = 0.00
Multiple Dependent Claim Present and Fee Not Previously Paid					\$140.00	\$280.00
Total					\$	\$0.00

- ☒ Applicant(s) believe that no (additional) Extension of Time is required; however, if it is determined that such an extension is required, Applicant(s) hereby petition that such an extension be granted and authorize the Commissioner to charge the required fees for an Extension of Time under 37 CFR 1.136 to Deposit Account No. 500388.
- ☒ Please charge the required fees, or any additional fees required to facilitate filing the enclosed response, to Deposit Account No. 500388 (Order No. KLA1P012).

Respectfully submitted,  
BEYER WEAVER & THOMAS, LLP

  
Phillip P. Lee  
Reg. No. 46,866

P.O. Box 778  
Berkeley, CA 94704-0778



PATENT

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**IN THE UNITED STATES PATENT AND TRADEMARK OFFICE**

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**STATEMENT OF THE SUBSTANCE OF THE INTERVIEW**  
**per 37 C.F.R. §1.133(b)**

Commissioner for Patents  
P.O. Box 1450  
Alexandria, VA 22313-1450

Dear Sir:

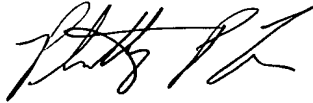
In response to the Interview Summary dated October 21, 2003, please enter this Statement of the Substance of the Interview. Per today's telephone conversation with Examiner Fernandez it is understood that the deadline for submitting this Statement of the Substance of the Interview has been extended one month from today, February 3, 2004.

Examiner Fernandez is thanked for the telephone interview conducted on October 1, 2003. Claim 21 was discussed during the interview. The prior art references of Soezima and Wallace et al. were discussed.

Amendments for addressing the rejection under 35 U.S.C. §112 were discussed. Such

amendments involve clarifying that "collected data" is "raw data." The patentability of claim 21, which pertains to a modeling algorithm, was discussed.

Respectfully submitted,  
BEYER WEAVER & THOMAS, LLP

A handwritten signature in black ink, appearing to read "Phillip P. Lee", written over a horizontal line.

Phillip P. Lee  
Reg. No. 46,866

BEYER WEAVER & THOMAS, LLP  
P.O. Box 778  
Berkeley, CA 94704-0778

Telephone: (510) 843-6200  
Facsimile: (510) 843-6203